

Applications

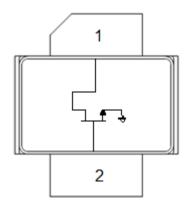
- Military radar
- Civilian radar
- · Professional and military radio communications
- Test instrumentation
- Wideband or narrowband amplifiers
- Jammers

Product Features

- Frequency: DC to 3.5 GHz
- Output Power (P_{3dB}): 64 W at 3.3 GHz
- Linear Gain: 16 dB at 3.3 GHz
- Operating Voltage: 28 V
- Low thermal resistance package



Functional Block Diagram



General Description

The TriQuint T2G4005528-FS is a 55 W (P_{3dB}) discrete GaN on SiC HEMT which operates from DC to 3.5 GHz. The device is constructed with TriQuint's proven TQGaN25 production process, which features advanced field plate techniques to optimize power and efficiency at high drain bias operating conditions. This optimization can potentially lower system costs in terms of fewer amplifier line-ups and lower thermal management costs.

Lead-free and ROHS compliant

Evaluation boards are available upon request.

Pin Configuration

| Pin No. | Label |
|---------|-------------------------|
| 1 | V _D / RF OUT |
| 2 | V _G / RF IN |
| Flange | Source |

| Ordering Information | | | | |
|------------------------|-------|-----------------------------------|--|--|
| Part | ECCN | Description | | |
| T2G4005528-FS | EAR99 | Packaged part Flangeless | | |
| T2G4005528-FS- EVB1 | EAR99 | 3.0-3.5 GHz Evaluation Board | | |
| T2G405528-FS- EVB2 | EAR99 | 1.0 – 1.4 GHz Evaluation Board | | |

Absolute Maximum Ratings⁽¹⁾

| Parameter | Value |
|--|-----------------------------|
| Breakdown Voltage (BV _{DG}) | 100 V (Min.) ⁽²⁾ |
| Drain Gate Voltage (V _{DG}) | 40 V |
| Gate Voltage Range (V _G) | -7 to 0 V |
| Drain Current (I _D) | 20 A |
| Gate Current (I _G) | -20 to 56 mA |
| Power Dissipation (P _D) | 90 W |
| RF Input Power, CW, T = 25 ℃ (P _{IN}) | 43 dBm |
| Channel Temperature (T _{CH}) | 275 ℃ |
| Mounting Temperature (30 Seconds) | 320 °C |
| Storage Temperature | -40 to 150 ℃ |

Recommended Operating Conditions

| Parameter | Value |
|--|----------------|
| Drain Voltage (V _D) | 28 V (Typ.) |
| Drain Quiescent Current (I _{DQ}) | 200 mA (Typ.) |
| Peak Drain Current (I_D) | 4.0 A (Typ.) |
| Gate Voltage (V _G) | -2.95 V (Typ.) |
| Channel Temperature (T _{CH}) | 225 ℃ (Max) |
| Power Dissipation, CW (P _D) | 66 (Max) |
| Power Dissipation, Pulse (P _D) | 70 (Max) |

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions.

1. Operation of this device outside the parameter ranges given above may cause permanent damage. These are stress ratings only, and functional operation of the device at these conditions is not implied.

2. Established at Vgs = -8V and Idq = 20mA

RF Characterization – Load Pull Performance at 3.0 GHz⁽¹⁾

Test conditions unless otherwise noted: $T_A = 25$ °C, $V_D = 28$ V, $I_{DQ} = 200$ mA

| Symbol | Parameter | Min | Typical | Max | Units |
|--------------------|--|-----|---------|-----|-------|
| G _{LIN} | Linear Gain | | 16.8 | | dB |
| P _{3dB} | Output Power at 3 dB Gain Compression | | 66.0 | | W |
| DE _{3dB} | Drain Efficiency at 3 dB Gain Compression 61.0 | | % | | |
| PAE _{3dB} | Power-Added Efficiency at 3 dB Gain | | 58.4 | | % |
| G _{3dB} | Gain at 3 dB Compression | | 13.8 | | dB |

Notes:

1. V_{DS} = 28 V, I_{DQ} = 200 mA; Pulse: 100 $\mu s,$ 20%

RF Characterization – Load Pull Performance at 3.5 GHz⁽¹⁾

| Test condition | Test conditions unless otherwise noted: $T_A = 25 ^{\circ}C$, $V_D = 28 ^{\circ}V$, $I_{DQ} = 200 ^{\circ}MA$ | | | | | |
|--------------------|---|--|---------|-----|-------|--|
| Symbol | nbol Parameter | | Typical | Max | Units | |
| G _{LIN} | Linear Gain | | 16.7 | | dB | |
| P _{3dB} | Output Power at 3 dB Gain Compression | | 64.5 | | W | |
| DE _{3dB} | Drain Efficiency at 3 dB Gain Compression | | 59.2 | | % | |
| PAE _{3dB} | Power-Added Efficiency at 3 dB Gain | | 56.7 | | % | |
| G _{3dB} | Gain at 3 dB Compression | | 13.7 | | dB | |

Notes:

1. $V_{DS} = 28 \text{ V}, I_{DQ} = 200 \text{ mA}; \text{Pulse: } 100 \mu \text{s}, 20\%$

RF Characterization – Performance at 3.3 GHz ^(1, 2)

| Test conditions unless otherwise noted: T _A = 25 °C, V _D = 28 V, I _{DQ} = 300 mA | |
|---|--|
| | |

| Symbol | Parameter | Min | Typical | Max | Units |
|--------------------|---|------|---------|------|-------|
| G _{LIN} | Linear Gain | 14.0 | 16.0 | | dB |
| P _{3dB} | Output Power at 3 dB Gain Compression | 55.0 | 62.5 | | W |
| DE _{3dB} | Drain Efficiency at 3 dB Gain Compression | 50.0 | 52.0 | | % |
| PAE _{3dB} | Power-Added Efficiency at 3 dB Gain | 45.0 | 49.0 | | % |
| G _{3dB} | Gain at 3 dB Compression | 11.0 | 13.0 | | dB |
| Vg | Gate voltage | -3.2 | -2.9 | -2.5 | V |

Notes:

1. Performance at 3.3 GHz in the 3.0 to 3.5 GHz Evaluation Board

2. $V_{DS} = 28 \text{ V}, I_{DQ} = 200 \text{ mA}; \text{ Pulse: } 100 \mu \text{s}, 20\%$

Gate Leakage

| Test conditions unless otherwise noted: $T_A = 25 ^{\circ}C$, $V_{GS} = -5 ^{\circ}V$, $V_{DS} = 28 ^{\circ}V$ | | | | | |
|--|----------------------|-----|---------|-----|-------|
| Symbol | Parameter | Min | Typical | Max | Units |
| I _{G-leak} | Leakage Gate Current | | | 4 | mA |

RF Characterization – Mismatched Ruggedness at 3.50 GHz⁽¹⁾

Test conditions unless otherwise noted: $T_A = 25$ °C, $V_D = 28$ V, $I_{DQ} = 200$ mA

| Symbol | Parameter | Typical |
|--------|-------------------------------|---------|
| VSWR | Impedance Mismatch Ruggedness | 10:1 |

Notes:

1. V_{DS} = 28 V, I_{DQ} = 200 mA, CW at P_{1dB}

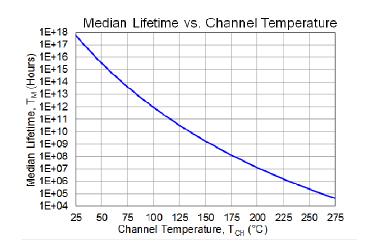
Thermal and Reliability Information

| Parameter | Test Conditions | Value | Units |
|--|------------------|-------|-------|
| Thermal Resistance (θ_{JC}) | | 2.1 | °C/W |
| Channel Temperature (T _{CH}) | DC at 85 °C Case | 225 | ℃ |

Notes:

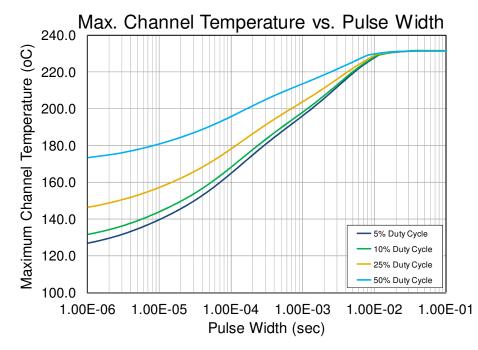
Thermal resistance measured to bottom of package

Median Lifetime



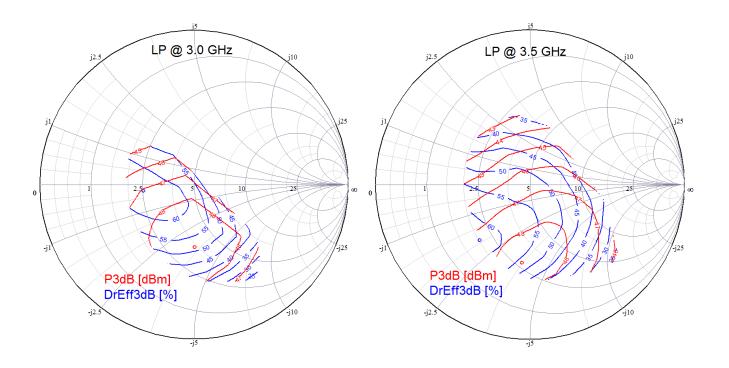
Maximum Channel Temperature

 $T_{\text{BASE}} = 85 \,^{\circ}\text{C}, \ P_{\text{D}} = 70 \text{ W}$



Load Pull Smith Charts ^(1, 2)

RF performance that the device typically exhibits when placed in the specified impedance environment. The impedances are not the impedances of the device, they are the impedances presented to the device via an RF circuit or load-pull system. The impedances listed follow an optimized trajectory to maintain high power and high efficiency.

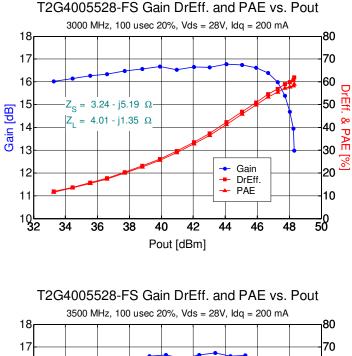


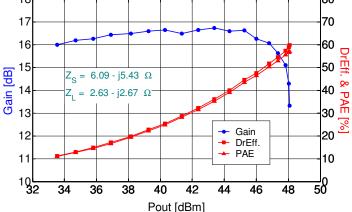
Notes:

- 1. Test Conditions: $V_{DS} = 28 \text{ V}$, $I_{DQ} = 200 \text{ mA}$
- 2. Test Signal: Pulse Width = 100 µsec, Duty Cycle = 20%

Typical Performance

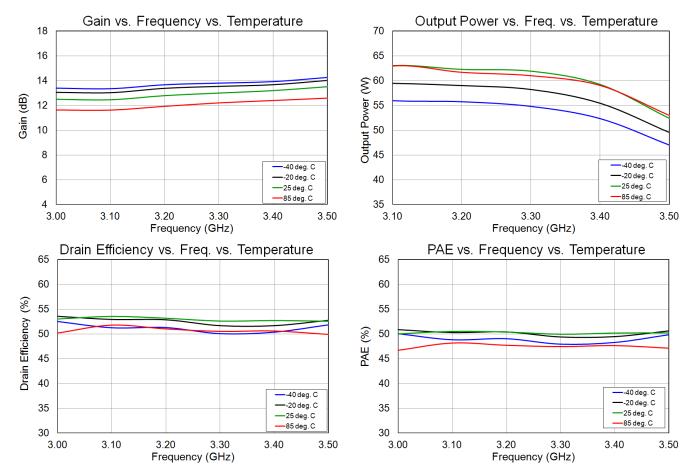
Performance is based on compromised impedance point and measured at DUT reference plane.





Performance Over Temperature (1, 2)

Performance measured in TriQuint's 3.0 GHz to 3.5 GHz Evaluation Board at 3 dB compression.



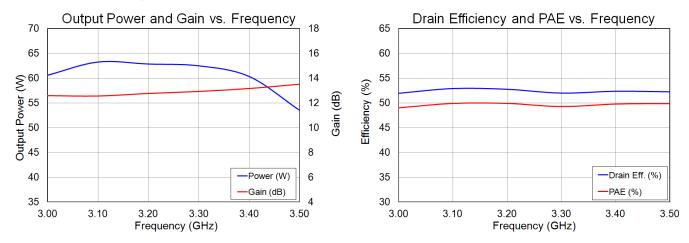
Notes:

2. Test Signal: Pulse Width = 100 $\mu s,$ Duty Cycle = 20%

^{1.} Test Conditions: $V_{DS} = 28 \text{ V}$, $I_{DQ} = 300 \text{ mA}$

Evaluation Board Performance (1, 2)

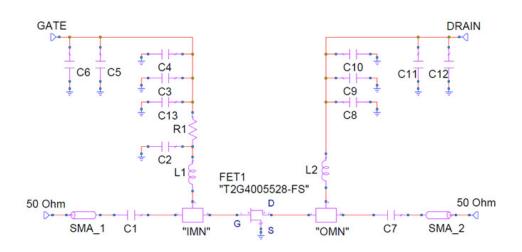
Performance at 3 dB Compression



Notes:

- 1. Test Conditions: V_{DS} = 28 V, I_{DQ} = 300 mA
- 2. Test Signal: Pulse Width = 100 μ s, Duty Cycle = 20 %

Application Circuit



Bias-up Procedure

Set gate voltage (V_G) to -5.0V

Set drain voltage (V_D) to 28 V $\,$

Slowly increase V_G until quiescent I_D is 200 mA.

Apply RF signal

Bias-down Procedure

Turn off RF signal

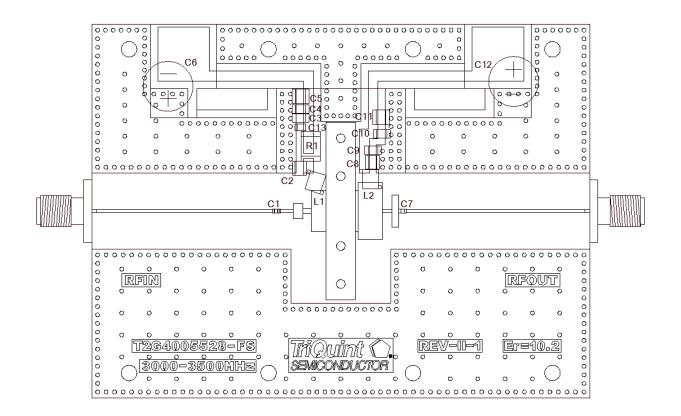
Turn off V_{D} and wait 1 second to allow drain capacitor dissipation

Turn off V_G

TiQuint 55W, 28V DC – 3.5 GHz, GaN RF Power Transistor

Evaluation Board Layout

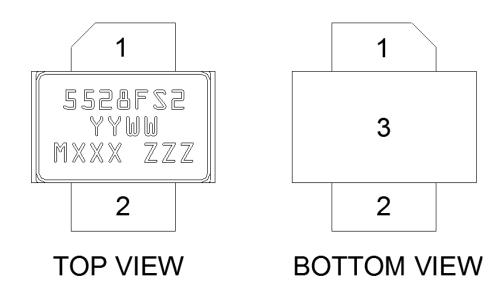
Top RF layer is 0.025" thick Rogers RO3210, $\varepsilon_r = 10.2$. The pad pattern shown has been developed and tested for optimized assembly at TriQuint Semiconductor. The PCB land pattern has been developed to accommodate lead and package tolerances.



Bill of Materials

| Reference Design | Value | Qty | Manufacturer | Part Number |
|-------------------------|----------|-----|-----------------|-------------------|
| C1, C7 | 47 pF | 2 | ATC | 100A470JW |
| C2, C8 | 82 pF | 2 | ATC | 100B820JW |
| C3, C9 | 2200 pF | 2 | Vitramon | VJ1206Y222KRA |
| C4, C10 | 22000 pF | 2 | Vitramon | 48C4641 |
| C5, C11 | 1 uF | 2 | Allied | 213-0366 |
| C6, C12 | 470 uF | 2 | Illinois Cap | 477KXM035M |
| L1, L2 | 12.5 nH | 2 | Coilcraft | A04T_JL |
| R1 | 2.4 Ohm | 1 | Vishay Dale | CRCW25122R40JNEG |
| C13 | 2400 pF | 1 | Dielectric Labs | C08BL242X-5UN-X0B |

Pin Layout



Note:

The T2G4005528-FS will be marked with the "5528FS2" designator and a lot code marked below the part designator. The "YY" represents the last two digits of the calendar year the part was manufactured, the "WW" is the work week of the assembly lot start, the "MXXX" is the production lot number, and the "ZZZ" is an auto-generated serial number.

| Pin Description | | |
|-----------------|-------------------------|---|
| Pin | Symbol | Description |
| 1 | V _D / RF OUT | Drain voltage / RF Output matched to 50 ohms; see EVB Layout on page 9 as an example. |
| 2 | V _G / RF IN | Gate voltage / RF Input matched to 50 ohms; see EVB Layout on page 9 as an example. |
| 3 | Flange | Source connected to ground; see EVB Layout on page 9 as an example. |

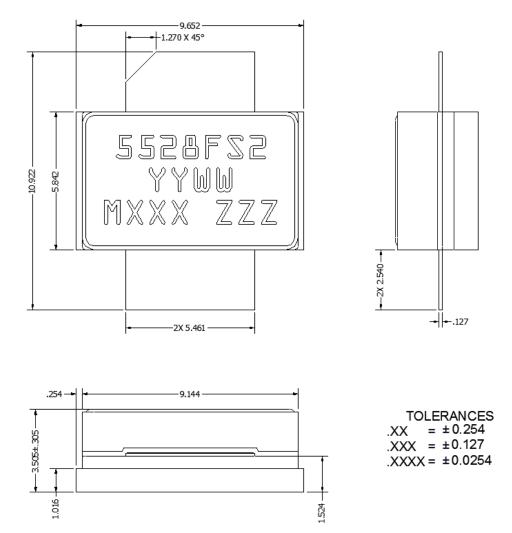
Notes:

Thermal resistance measured to bottom of package



Mechanical Information

All dimensions are in millimeters.



Note:

This package is lead-free/RoHS-compliant. The plating material on the leads is NiAu. It is compatible with both lead-free (maximum 260 °C reflow temperature) and tin-lead (maximum 245 °C reflow temperature) soldering processes.



Product Compliance Information

ESD Sensitivity Ratings



Caution! ESD-Sensitive Device

ESD Rating:Class 1AValue:Passes ≥ 250 V min.Test:Human Body Model (HBM)Standard:JEDEC Standard JESD22-A114

MSL Rating

Level 3 at +260 $^{\circ}\mathrm{C}$ convection reflow The part is rated Moisture Sensitivity Level 3 at 260 $^{\circ}\mathrm{C}$ per JEDEC standard IPC/JEDEC J-STD-020.

ECCN

US Department of Commerce EAR99

Recommended Soldering Temperature Profile



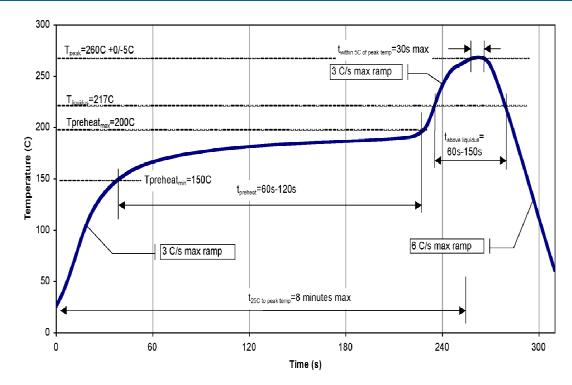
Compatible with the latest version of J-STD-020, Lead free solder, 260° C

RoHs Compliance

This part is compliant with EU 2002/95/EC RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment).

This product also has the following attributes:

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A (C₁₅H₁₂Br₄0₂) Free
- PFOS Free
- SVHC Free



TiQuint 55W, 28V DC – 3.5 GHz, GaN RF Power Transistor

Contact Information

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